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### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Active
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I <sup>2</sup> C, IrDA, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, IR, LCD, POR, PWM, WDT
Number of I/O	68
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 28x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	80-LQFP
Supplier Device Package	80-LQFP (14x14)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/stmicroelectronics/stm8l152m8t7">https://www.e-xfl.com/product-detail/stmicroelectronics/stm8l152m8t7</a>

## 2.2 Device overview

**Table 2. High-density and medium+ density STM8L15xx6/8 low power device features and peripheral counts**

Features		STM8L15xC8	STM8L15xK8	STM8L15xR8	STM8L15xM8	STM8L15xR6
Flash (Kbyte)		64	64	64	64	32
Data EEPROM (Kbyte)		2	2	2	2	1
RAM (Kbyte)		4	4	4	4	2
LCD		8x24 or 4x28 <sup>(1)</sup>	4x15 <sup>(1)</sup>	8x36 or 4x40 <sup>(1)</sup>	8x40 or 4x44 <sup>(1)</sup>	8x36 or 4x40 <sup>(1)</sup>
Timers	Basic	1 (8-bit)	1 (8-bit)	1 (8-bit)	1 (8-bit)	1 (8-bit)
	General purpose	3 (16-bit)	3 (16-bit)	3 (16-bit)	3 (16-bit)	3 (16-bit)
	Advanced control	1 (16-bit)	1 (16-bit)	1 (16-bit)	1 (16-bit)	1 (16-bit)
Communication interfaces	SPI	2	1	2	2	2
	I2C	1	1	1	1	1
	USART	3	2	3	3	3
GPIOs		41 <sup>(2)</sup>	28 <sup>(2)</sup>	54 <sup>(2)</sup>	68 <sup>(2)</sup>	54 <sup>(2)</sup>
12-bit synchronized ADC (number of channels)		1 (25)	1 (18)	1 (28)	1 (28)	1 (28)
12-Bit DAC		2	1	2	2	2
Number of channels		2	1	2	2	2
Comparators (COMP1/COMP2)		2	2	2	2	2
Others		RTC, window watchdog, independent watchdog, 16-MHz and 38-kHz internal RC, 1- to 16-MHz and 32-kHz external oscillator				
CPU frequency		16 MHz				
Operating voltage		1.8 to 3.6 V (down to 1.65 V at power-down) with BOR 1.65 to 3.6 V without BOR				
Operating temperature		-40 to +85 °C / -40 to +105 °C / -40 to +125 °C				
Packages		UFQFPN48 LQFP48	WLCSP32	LQFP64	LQFP80	LQFP64

1. STM8L152x6/8 versions only.

2. The number of GPIOs given in this table includes the NRST/PA1 pin but the application can use the NRST/PA1 pin as general purpose output only (PA1).

Table 5. High-density and medium+ density STM8L15x pin description (continued)

Pin number				Pin name	Type	I/O level	Input			Output			Main function (after reset)	Default alternate function
LQFP80	LQFP64	UFQFPN48 and LQFP48	WLCSP32				floating	wpu	Ext. interrupt	High sink/source	OD	PP		
62	50	-	-	PG5/LCD_SEG33/ SPI2_SCK	I/O	FT <sup>(6)</sup>	X	X	X	HS	X	X	Port G5	LCD segment 33 / SPI2 clock
63	51	-	-	PG6/LCD_SEG34/ SPI2_MOSI	I/O	FT <sup>(6)</sup>	X	X	X	HS	X	X	Port G6	LCD segment 34 / SPI2 master out- slave in
64	52	-	-	PG7/LCD_SEG35/ SPI2_MISO	I/O	FT <sup>(6)</sup>	X	X	X	HS	X	X	Port G7	LCD segment 35 / SPI2 master in- slave out
23	19	14	.(4)	PE0/LCD_SEG1 <sup>(3)</sup> / TIM5_CH2	I/O	FT <sup>(6)</sup>	X	X	X	HS	X	X	Port E0	LCD segment 1/ Timer 5 channel 2
24	20	15	.(4)	PE1/TIM1_CH2N /LCD_SEG2 <sup>(3)</sup>	I/O	FT <sup>(6)</sup>	X	X	X	HS	X	X	Port E1	Timer 1 - inverted channel 2 / LCD segment 2
25	21	16	.(4)	PE2/TIM1_CH3N /LCD_SEG3 <sup>(3)</sup> / [CCO] <sup>(2)</sup>	I/O	FT <sup>(6)</sup>	X	X	X	HS	X	X	Port E2	Timer 1 - inverted channel 3 / LCD segment 3 / [Configurable clock output]
26	-	-	-	PE3/LCD_SEG4 <sup>(3)</sup>	I/O	FT <sup>(6)</sup>	X	X	X	HS	X	X	Port E3	LCD segment 4
-	22	17	H2	PE3/LCD_SEG4 <sup>(3)</sup> / USART2_RX	I/O	FT <sup>(6)</sup>	X	X	X	HS	X	X	Port E3	LCD segment 4/ USART2 receive
27	-	-	-	PE4/LCD_SEG5 <sup>(3)</sup> / DAC_TRIG1	I/O	FT <sup>(6)</sup>	X	X	X	HS	X	X	Port E4	LCD segment 5/ DAC 1 trigger
-	23	18	H3	PE4/LCD_SEG5 <sup>(3)</sup> / DAC_TRIG2/USART2_TX	I/O	FT <sup>(6)</sup>	X	X	X	HS	X	X	Port E4	LCD segment 5/ DAC 2 trigger/ USART2 transmit
28	-	-	-	PE5/LCD_SEG6 <sup>(3)</sup> / ADC1_IN23/[COMP1_INP]/ [COMP2_INP]	I/O	FT <sup>(6)</sup>	X	X	X	HS	X	X	Port E5	LCD segment 6 / ADC1_IN23/ [Comparator 1 positive input] / [Comparator 2 positive input]
-	24	19	.(4)	PE5/LCD_SEG6 <sup>(3)</sup> / ADC1_IN23/[COMP1_INP]/ [COMP2_INP] / USART2_CK	I/O	FT <sup>(6)</sup>	X	X	X	HS	X	X	Port E5	LCD segment 6 / ADC1_IN23/ [Comparator 1 positive input] / [Comparator 2 positive input] /USART2 synchronous clock

Table 8. I/O port hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 500F	Port D	PD_ODR	Port D data output latch register	0x00
0x00 5010		PD_IDR	Port D input pin value register	0xXX
0x00 5011		PD_DDR	Port D data direction register	0x00
0x00 5012		PD_CR1	Port D control register 1	0x00
0x00 5013		PD_CR2	Port D control register 2	0x00
0x00 5014	Port E	PE_ODR	Port E data output latch register	0x00
0x00 5015		PE_IDR	Port E input pin value register	0xXX
0x00 5016		PE_DDR	Port E data direction register	0x00
0x00 5017		PE_CR1	Port E control register 1	0x00
0x00 5018		PE_CR2	Port E control register 2	0x00
0x00 5019	Port F	PF_ODR	Port F data output latch register	0x00
0x00 501A		PF_IDR	Port F input pin value register	0xXX
0x00 501B		PF_DDR	Port F data direction register	0x00
0x00 501C		PF_CR1	Port F control register 1	0x00
0x00 501D		PF_CR2	Port F control register 2	0x00
0x00 501E	Port G	PG_ODR	Port G data output latch register	0x00
0x00 501F		PG_IDR	Port G input pin value register	0xXX
0x00 5020		PG_DDR	Port G data direction register	0x00
0x00 5021		PG_CR1	Port G control register 1	0x00
0x00 5022		PG_CR2	Port G control register 2	0x00
0x00 5023	Port H	PH_ODR	Port H data output latch register	0x00
0x00 5024		PH_IDR	Port H input pin value register	0xXX
0x00 5025		PH_DDR	Port H data direction register	0x00
0x00 5026		PH_CR1	Port H control register 1	0x00
0x00 5027		PH_CR2	Port H control register 2	0x00
0x00 5028	Port I	PI_ODR	Port I data output latch register	0x00
0x00 5029		PI_IDR	Port I input pin value register	0xXX
0x00 502A		PI_DDR	Port I data direction register	0x00
0x00 502B		PI_CR1	Port I control register 1	0x00
0x00 502C		PI_CR2	Port I control register 2	0x00

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 516A	RTC	RTC_CALRH	Calibration register high	0x00 <sup>(1)</sup>
0x00 516B		RTC_CALRL	Calibration register low	0x00 <sup>(1)</sup>
0x00 516C		RTC_TCR1	Tamper control register 1	0x00 <sup>(1)</sup>
0x00 516D		RTC_TCR2	Tamper control register 2	0x00 <sup>(1)</sup>
0x00 516E to 0x00 518A	Reserved area			
0x00 5190	CSSLSE	CSSLSE_CSR	CSS on LSE control and status register	0x00 <sup>(1)</sup>
0x00 519A to 0x00 51FF	Reserved area			
0x00 5200	SPI1	SPI1_CR1	SPI1 control register 1	0x00
0x00 5201		SPI1_CR2	SPI1 control register 2	0x00
0x00 5202		SPI1_ICR	SPI1 interrupt control register	0x00
0x00 5203		SPI1_SR	SPI1 status register	0x02
0x00 5204		SPI1_DR	SPI1 data register	0x00
0x00 5205		SPI1_CRCPR	SPI1 CRC polynomial register	0x07
0x00 5206		SPI1_RXCR	SPI1 Rx CRC register	0x00
0x00 5207		SPI1_TXCR	SPI1 Tx CRC register	0x00
0x00 5208 to 0x00 520F	Reserved area (8 byte)			
0x00 5210	I2C1	I2C1_CR1	I2C1 control register 1	0x00
0x00 5211		I2C1_CR2	I2C1 control register 2	0x00
0x00 5212		I2C1_FREQR	I2C1 frequency register	0x00
0x00 5213		I2C1_OARL	I2C1 own address register low	0x00
0x00 5214		I2C1_OARH	I2C1 own address register high	0x00
0x00 5215		I2C1_OARH	I2C1 own address register for dual mode	0x00
0x00 5216		I2C1_DR	I2C1 data register	0x00
0x00 5217		I2C1_SR1	I2C1 status register 1	0x00
0x00 5218		I2C1_SR2	I2C1 status register 2	0x00
0x00 5219		I2C1_SR3	I2C1 status register 3	0x0X
0x00 521A		I2C1_ITR	I2C1 interrupt control register	0x00
0x00 521B		I2C1_CCRL	I2C1 clock control register low	0x00
0x00 521C		I2C1_CCRH	I2C1 clock control register high	0x00
0x00 521D		I2C1_TRISER	I2C1 TRISE register	0x02
0x00 521E		I2C1_PECR	I2C1 packet error checking register	0x00

**Table 9. General hardware register map (continued)**

Address	Block	Register label	Register name	Reset status
0x00 52B0	TIM1	TIM1_CR1	TIM1 control register 1	0x00
0x00 52B1		TIM1_CR2	TIM1 control register 2	0x00
0x00 52B2		TIM1_SMCR	TIM1 Slave mode control register	0x00
0x00 52B3		TIM1_ETR	TIM1 external trigger register	0x00
0x00 52B4		TIM1_DER	TIM1 DMA1 request enable register	0x00
0x00 52B5		TIM1_IER	TIM1 Interrupt enable register	0x00
0x00 52B6		TIM1_SR1	TIM1 status register 1	0x00
0x00 52B7		TIM1_SR2	TIM1 status register 2	0x00
0x00 52B8		TIM1_EGR	TIM1 event generation register	0x00
0x00 52B9		TIM1_CCMR1	TIM1 Capture/Compare mode register 1	0x00
0x00 52BA		TIM1_CCMR2	TIM1 Capture/Compare mode register 2	0x00
0x00 52BB		TIM1_CCMR3	TIM1 Capture/Compare mode register 3	0x00
0x00 52BC		TIM1_CCMR4	TIM1 Capture/Compare mode register 4	0x00
0x00 52BD		TIM1_CCER1	TIM1 Capture/Compare enable register 1	0x00
0x00 52BE		TIM1_CCER2	TIM1 Capture/Compare enable register 2	0x00
0x00 52BF		TIM1_CNTRH	TIM1 counter high	0x00
0x00 52C0		TIM1_CNTRL	TIM1 counter low	0x00
0x00 52C1		TIM1_PSCRH	TIM1 prescaler register high	0x00
0x00 52C2		TIM1_PSCRL	TIM1 prescaler register low	0x00
0x00 52C3		TIM1_ARRH	TIM1 Auto-reload register high	0xFF
0x00 52C4		TIM1_ARRL	TIM1 Auto-reload register low	0xFF
0x00 52C5		TIM1_RCR	TIM1 Repetition counter register	0x00
0x00 52C6		TIM1_CCR1H	TIM1 Capture/Compare register 1 high	0x00
0x00 52C7		TIM1_CCR1L	TIM1 Capture/Compare register 1 low	0x00
0x00 52C8		TIM1_CCR2H	TIM1 Capture/Compare register 2 high	0x00
0x00 52C9		TIM1_CCR2L	TIM1 Capture/Compare register 2 low	0x00
0x00 52CA		TIM1_CCR3H	TIM1 Capture/Compare register 3 high	0x00
0x00 52CB		TIM1_CCR3L	TIM1 Capture/Compare register 3 low	0x00
0x00 52CC		TIM1_CCR4H	TIM1 Capture/Compare register 4 high	0x00
0x00 52CD		TIM1_CCR4L	TIM1 Capture/Compare register 4 low	0x00
0x00 52CE		TIM1_BKR	TIM1 break register	0x00
0x00 52CF		TIM1_DTR	TIM1 dead-time register	0x00
0x00 52D0		TIM1_OISR	TIM1 output idle state register	0x00
0x00 52D1		TIM1_DCR1	DMA1 control register 1	0x00

**Table 9. General hardware register map (continued)**

Address	Block	Register label	Register name	Reset status
0x00 53C8 to 0x00 53DF	Reserved area			
0x00 53E0	USART2	USART2_SR	USART2 status register	0xC0
0x00 53E1		USART2_DR	USART2 data register	0xFF
0x00 53E2		USART2_BRR1	USART2 baud rate register 1	0x00
0x00 53E3		USART2_BRR2	USART2 baud rate register 2	0x00
0x00 53E4		USART2_CR1	USART2 control register 1	0x00
0x00 53E5		USART2_CR2	USART2 control register 2	0x00
0x00 53E6		USART2_CR3	USART2 control register 3	0x00
0x00 53E7		USART2_CR4	USART2 control register 4	0x00
0x00 53E8		USART2_CR5	USART2 control register 5	0x00
0x00 53E9		USART2_GTR	USART2 guard time register	0x00
0x00 53EA		USART2_PSCR	USART2 prescaler register	0x00
0x00 53EB to 0x00 53EF	Reserved area			
0x00 53F0	USART3	USART3_SR	USART3 status register	0xC0
0x00 53F1		USART3_DR	USART3 data register	0xFF
0x00 53F2		USART3_BRR1	USART3 baud rate register 1	0x00
0x00 53F3		USART3_BRR2	USART3 baud rate register 2	0x00
0x00 53F4		USART3_CR1	USART3 control register 1	0x00
0x00 53F5		USART3_CR2	USART3 control register 2	0x00
0x00 53F6		USART3_CR3	USART3 control register 3	0x00
0x00 53F7		USART3_CR4	USART3 control register 4	0x00
0x00 53F8		USART3_CR5	USART3 control register 5	0x00
0x00 53F9		USART3_GTR	USART3 guard time register	0x00
0x00 53FA		USART3_PSCR	USART3 prescaler register	0x00
0x00 53FB to 0x00 53FF	Reserved area			

Table 11. Interrupt mapping (continued)

IRQ No.	Source block	Description	Wakeup from Halt mode	Wakeup from Active-halt mode	Wakeup from Wait (WFI mode)	Wakeup from Wait (WFE mode) <sup>(1)</sup>	Vector address
20	TIM2/ USART2	Capture/Compare/USART 2 interrupt	-	-	Yes	Yes <sup>(3)</sup>	0x00 8058
21	TIM3/ USART3	TIM3 Update /Overflow/Trigger/Break/ USART3 transmission complete/transmit data register empty interrupt	-	-	Yes	Yes <sup>(3)</sup>	0x00 805C
22	TIM3/ USART3	TIM3 Capture/Compare/ USART3 Receive register data full/overrun/idle line detected/parity error/ interrupt	-	-	Yes	Yes <sup>(3)</sup>	0x00 8060
23	TIM1	Update /overflow/trigger/ COM	-	-	-	Yes <sup>(3)</sup>	0x00 8064
24	TIM1	Capture/Compare	-	-	-	Yes <sup>(3)</sup>	0x00 8068
25	TIM4	Update/overflow/trigger	-	-	Yes	Yes <sup>(3)</sup>	0x00 806C
26	SPI1	End of Transfer	Yes	Yes	Yes	Yes <sup>(3)</sup>	0x00 8070
27	USART 1/ TIM5	USART1 transmission complete/transmit data register empty/ TIM5 update/overflow/ trigger/break	-	-	Yes	Yes <sup>(3)</sup>	0x00 8074
28	USART 1/ TIM5	USART1 Receive register data full/overrun/idle line detected/parity error/ TIM5 capture/compare	-	-	Yes	Yes <sup>(3)</sup>	0x00 8078
29	I <sup>2</sup> C1/SPI2	I <sup>2</sup> C1 interrupt <sup>(5)</sup> / SPI2	Yes	Yes	Yes	Yes <sup>(3)</sup>	0x00 807C

1. The Low-power wait mode is entered when executing a WFE instruction in Low-power run mode.
2. The TLI interrupt is the logic OR between TIM2 overflow interrupt, and TIM4 overflow interrupts.
3. In WFE mode, this interrupt is served if it has been previously enabled. After processing the interrupt, the processor goes back to WFE mode. When this interrupt is configured as a wakeup event, the CPU wakes up and resumes processing.
4. The interrupt from PVD is logically OR-ed with Port E and F interrupts. Register EXTI\_CONF allows to select between Port E and Port F interrupt (see [External interrupt port select register \(EXTI\\_CONF\)](#) in the RM0031).
5. The device is woken up from Halt or Active-halt mode only when the address received matches the interface address.



## 7 Option bytes

Option bytes contain configurations for device hardware features as well as the memory protection of the device. They are stored in a dedicated memory block.

All option bytes can be modified in ICP mode (with SWIM) by accessing the EEPROM address. See [Table 12](#) for details on option byte addresses.

The option bytes can also be modified ‘on the fly’ by the application in IAP mode, except for the ROP, UBC and PCODESIZE values which can only be taken into account when they are modified in ICP mode (with the SWIM).

Refer to the STM8L15x/STM8L16x Flash programming manual (PM0054) and STM8 SWIM and debug manual (UM0470) for information on SWIM programming procedures.

**Table 12. Option byte addresses**

Address	Option name	Option byte No.	Option bits								Factory default setting
			7	6	5	4	3	2	1	0	
00 4800	Read-out protection (ROP)	OPT0	ROP[7:0]								0xAA
00 4802	UBC (User Boot code size)	OPT1	UBC[7:0]								0x00
00 4807	PCODESIZE	OPT2	PCODE[7:0]								0x00
00 4808	Independent watchdog option	OPT3 [3:0]	Reserved				WWDG _HALT	WWDG _HW	IWDG _HALT	IWDG _HW	0x00
00 4809	Number of stabilization clock cycles for HSE and LSE oscillators	OPT4	Reserved				LSECNT[1:0]		HSECNT[1:0]		0x00
00 480A	Brownout reset (BOR)	OPT5 [3:0]	Reserved				BOR_TH			BOR_ON	0x00
00 480B	Bootloader option bytes (OPTBL)	OPTBL [15:0]	OPTBL[15:0]								0x00
00 480C											0x00

Table 13. Option byte description (continued)

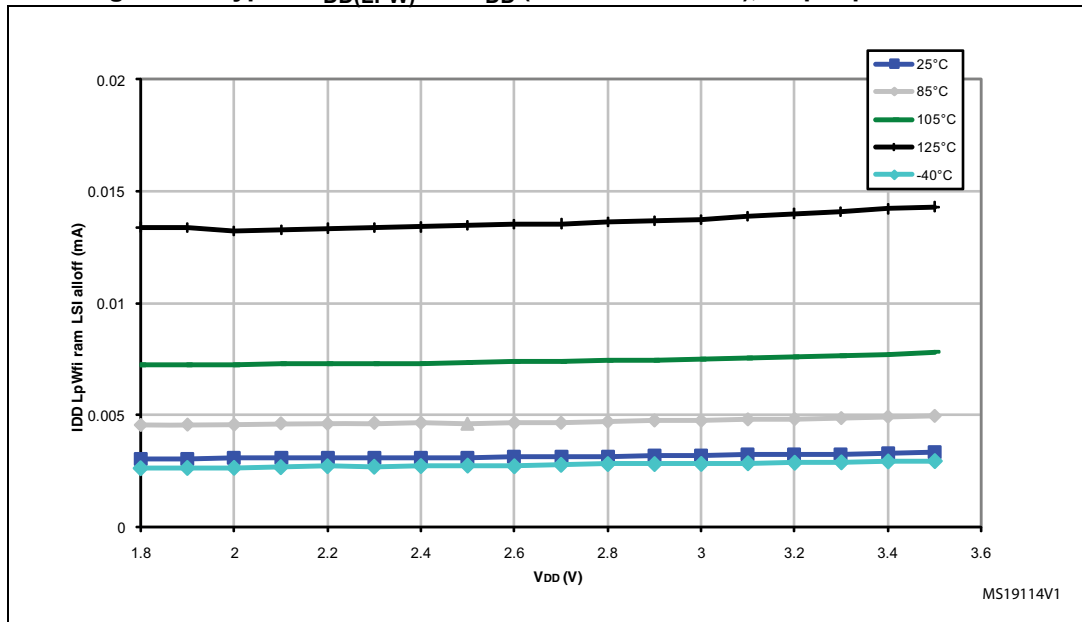
Option byte no.	Option description
OPT5	<b>BOR_ON:</b> 0: Brownout reset off 1: Brownout reset on
	<b>BOR_TH[3:1]:</b> Brownout reset thresholds. Refer to <a href="#">Table 19</a> for details on the thresholds according to the value of BOR_TH bits.
OPTBL	<b>OPTBL[15:0]:</b> This option is checked by the boot ROM code after reset. Depending on the content of addresses 00 480B, 00 480C and 0x8000 (reset vector) the CPU jumps to the bootloader or to the reset vector. Refer to the UM0560 bootloader user manual for more details.

9.3.2 Embedded reset and power control block characteristics

Table 19. Embedded reset and power control block characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
t <sub>VDD</sub>	V <sub>DD</sub> rise time rate	BOR detector enabled	0 <sup>(1)</sup>	-	∞ <sup>(1)</sup>	µs/V
		BOR detector disabled	0 <sup>(1)</sup>	-	1 <sup>(1)</sup>	ms/V
	V <sub>DD</sub> fall time rate	BOR detector enabled	20 <sup>(1)</sup>	-	∞ <sup>(1)</sup>	µs/V
		BOR detector disabled	Reset below voltage functional range			
t <sub>TEMP</sub>	Reset release delay	V <sub>DD</sub> rising BOR detector enabled	-	3	-	ms
		V <sub>DD</sub> rising BOR detector disabled	-	1	-	
V <sub>POR</sub>	Power-on reset threshold	Rising edge	1.3 <sup>(2)</sup>	1.5	1.65	V
V <sub>PDR</sub>	Power-down reset threshold	Falling edge	1.3 <sup>(2)</sup>	1.5	1.65	
V <sub>BOR0</sub>	Brown-out reset threshold 0 (BOR_TH[2:0]=000)	Falling edge	1.67	1.7	1.74	
		Rising edge	1.69	1.75	1.80	
V <sub>BOR1</sub>	Brown-out reset threshold 1 (BOR_TH[2:0]=001)	Falling edge	1.87	1.93	1.97	
		Rising edge	1.96	2.04	2.07	
V <sub>BOR2</sub>	Brown-out reset threshold 2 (BOR_TH[2:0]=010)	Falling edge	2.22	2.3	2.35	
		Rising edge	2.31	2.41	2.44	
V <sub>BOR3</sub>	Brown-out reset threshold 3 (BOR_TH[2:0]=011)	Falling edge	2.45	2.55	2.60	
		Rising edge	2.54	2.66	2.7	
V <sub>BOR4</sub>	Brown-out reset threshold 4 (BOR_TH[2:0]=100)	Falling edge	2.68	2.80	2.85	
		Rising edge	2.78	2.90	2.95	

Figure 19. Typical  $I_{DD(LPW)}$  vs.  $V_{DD}$  (LSI clock source), all peripherals OFF



1. Typical current consumption measured with code executed from RAM.

**LSE external clock (LSEBYP=1 in CLK\_ECKCR)**

The LSE is available on STM8L151xx and STM8L152xx devices only.

Subject to general operating conditions for  $V_{DD}$  and  $T_A$ .

**Table 30. LSE external clock characteristics**

Symbol	Parameter	Min.	Typ.	Max.	Unit
$f_{LSE\_ext}^{(1)}$	External clock source frequency		32.768		kHz
$V_{LSEH}^{(2)}$	OSC32_IN input pin high level voltage	$0.7 \times V_{DD}$		$V_{DD}$	V
$V_{LSEL}^{(2)}$	OSC32_IN input pin low level voltage	$V_{SS}$		$0.3 \times V_{DD}$	
$C_{in(LSE)}^{(1)}$	OSC32_IN input capacitance		0.6		pF
$I_{LEAK\_LSE}$	OSC32_IN input leakage current			$\pm 1$	$\mu A$

1. Guaranteed by design.
2. Data based on characterization results.

**HSE crystal/ceramic resonator oscillator**

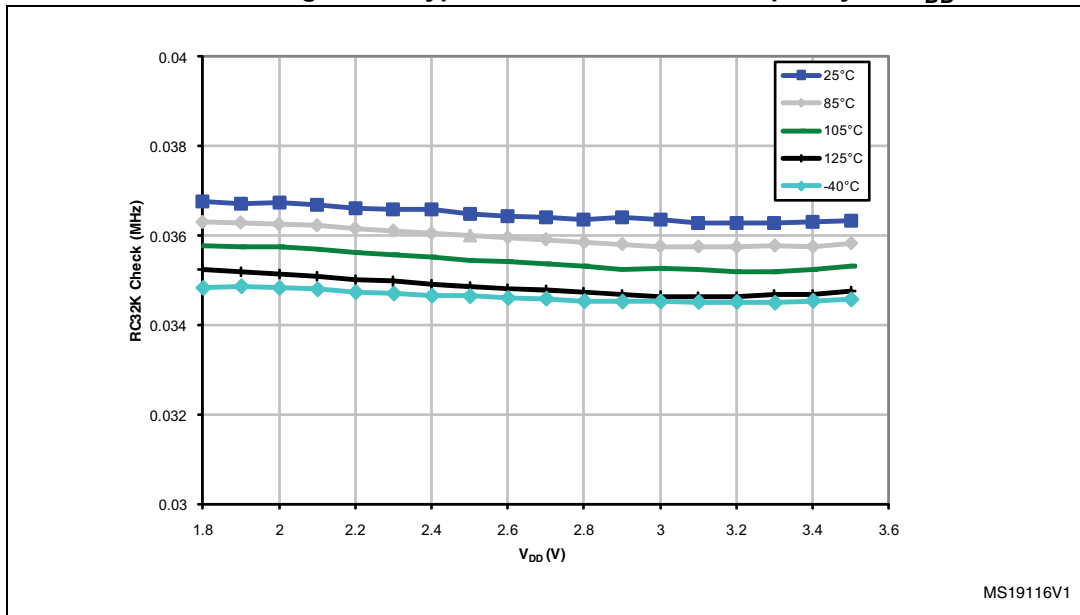
The HSE clock can be supplied with a 1 to 16 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph is based on characterization results with specified typical external components. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details (frequency, package, accuracy...).

**Table 31. HSE oscillator characteristics**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$f_{HSE}$	High speed external oscillator frequency		1		16	MHz
$R_F$	Feedback resistor			200		$k\Omega$
$C^{(1)(2)}$	Recommended load capacitance			20		pF
$I_{DD(HSE)}$	HSE oscillator power consumption	$C = 20 \text{ pF}$ , $f_{OSC} = 16 \text{ MHz}$			2.5 (startup) 0.7 (stabilized) <sup>(3)</sup>	mA
		$C = 10 \text{ pF}$ , $f_{OSC} = 16 \text{ MHz}$			2.5 (startup) 0.46 (stabilized) <sup>(3)</sup>	
$g_m$	Oscillator transconductance		$3.5^{(3)}$			$\text{mA/V}$
$t_{SU(HSE)}^{(4)}$	Startup time	$V_{DD}$ is stabilized		1		ms

1.  $C=C_{L1}=C_{L2}$  is approximately equivalent to  $2 \times$  crystal  $C_{LOAD}$ .
2. The oscillator selection can be optimized in terms of supply current using a high quality resonator with small  $R_m$  value. Refer to crystal manufacturer for more details
3. Guaranteed by design.
4.  $t_{SU(HSE)}$  is the startup time measured from the moment it is enabled (by software) to a stabilized 16 MHz oscillation. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer.

Figure 25. Typical LSI clock source frequency vs. V<sub>DD</sub>



MS19116V1

### 9.3.5 Memory characteristics

T<sub>A</sub> = -40 to 125 °C unless otherwise specified.

Table 35. RAM and hardware registers

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
V <sub>RM</sub>	Data retention mode <sup>(1)</sup>	Halt mode (or Reset)	1.65	-	-	V

1. Minimum supply voltage without losing data stored in RAM (in Halt mode or under Reset) or in hardware registers (only in Halt mode). Guaranteed by characterization.

### 9.3.8 Communication interfaces

#### SPI1 - Serial peripheral interface

Unless otherwise specified, the parameters given in [Table 43](#) are derived from tests performed under ambient temperature,  $f_{\text{SYSCLK}}$  frequency and  $V_{\text{DD}}$  supply voltage conditions summarized in [Section 9.3.1](#). Refer to I/O port characteristics for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO).

**Table 43. SPI1 characteristics**

Symbol	Parameter	Conditions <sup>(1)</sup>	Min.	Max.	Unit
$f_{\text{SCK}}$ $1/t_{\text{c(SCK)}}$	SPI1 clock frequency	Master mode	0	8	MHz
		Slave mode	0	8	
$t_{\text{r(SCK)}}$ $t_{\text{f(SCK)}}$	SPI1 clock rise and fall time	Capacitive load: C = 30 pF	-	30	ns
$t_{\text{su(NSS)}}^{(2)}$	NSS setup time	Slave mode	$4 \times 1/f_{\text{SYSCLK}}$	-	
$t_{\text{h(NSS)}}^{(2)}$	NSS hold time	Slave mode	80	-	
$t_{\text{w(SCKH)}}^{(2)}$ $t_{\text{w(SCKL)}}^{(2)}$	SCK high and low time	Master mode, $f_{\text{MASTER}} = 8 \text{ MHz}$ , $f_{\text{SCK}} = 4 \text{ MHz}$	105	145	
$t_{\text{su(MI)}}^{(2)}$ $t_{\text{su(SI)}}^{(2)}$	Data input setup time	Master mode	30	-	
		Slave mode	3	-	
$t_{\text{h(MI)}}^{(2)}$ $t_{\text{h(SI)}}^{(2)}$	Data input hold time	Master mode	15	-	
		Slave mode	0	-	
$t_{\text{a(SO)}}^{(2)(3)}$	Data output access time	Slave mode	-	$3 \times 1/f_{\text{SYSCLK}}$	
$t_{\text{dis(SO)}}^{(2)(4)}$	Data output disable time	Slave mode	30	-	
$t_{\text{v(SO)}}^{(2)}$	Data output valid time	Slave mode (after enable edge)	-	60	
$t_{\text{v(MO)}}^{(2)}$	Data output valid time	Master mode (after enable edge)	-	20	
$t_{\text{h(SO)}}^{(2)}$	Data output hold time	Slave mode (after enable edge)	15	-	
$t_{\text{h(MO)}}^{(2)}$		Master mode (after enable edge)	1	-	

- Parameters are given by selecting 10 MHz I/O output frequency.
- Values based on design simulation and/or characterization results.
- Min. time is for the minimum time to drive the output and max. time is for the maximum time to validate the data.
- Min. time is for the minimum time to invalidate the output and max. time is for the maximum time to put the data in Hi-Z.

### 9.3.10 Embedded reference voltage

In the following table, data are based on characterization results unless otherwise specified.

**Table 46. Reference voltage characteristics**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$I_{REFINT}$	Internal reference voltage consumption	-	-	1.4		$\mu\text{A}$
$T_{S\_VREFINT}^{(1)(2)}$	ADC sampling time when reading the internal reference voltage	-	-	5	10	$\mu\text{s}$
$I_{BUF}^{(1)}$	Internal reference voltage buffer consumption (used for ADC)	-	-	13.5	25	$\mu\text{A}$
$V_{REFINT\ out}$	Reference voltage output	-	1.202 <sup>(3)</sup>	1.224	1.242 <sup>(3)</sup>	V
$I_{LPBUF}^{(1)}$	Internal reference voltage low-power buffer consumption (used for comparators or output)	-	-	730	1200	nA
$I_{REFOUT}^{(1)(4)}$	Buffer output current	-	-		1	$\mu\text{A}$
$C_{REFOUT}$	Reference voltage output load	-	-		50	pF
$t_{VREFINT}^{(1)}$	Internal reference voltage startup time	-	-	2	3	ms
$t_{BUFEN}^{(1)(2)}$	Internal reference voltage buffer startup time once enabled	-	-		10	$\mu\text{s}$
$ACC_{VREFINT}^{(5)}$	Accuracy of $V_{REFINT}$ stored in the VREFINT_Factory_CONV byte	-	-		$\pm 5$	mV
$STAB_{VREFINT}$	Stability of $V_{REFINT}$ over temperature	$-40\text{ }^{\circ}\text{C} \leq T_A \leq 125\text{ }^{\circ}\text{C}$	-	20	50	ppm/ $^{\circ}\text{C}$
	Stability of $V_{REFINT}$ over temperature	$0\text{ }^{\circ}\text{C} \leq T_A \leq 50\text{ }^{\circ}\text{C}$	-	-	20	ppm/ $^{\circ}\text{C}$
$STAB_{VREFINT}$	Stability of $V_{REFINT}$ after 1000 hours	-	-	-	1000	ppm

1. Guaranteed by design.
2. Defined when ADC output reaches its final value  $\pm 1/2\text{LSB}$
3. Tested in production at  $V_{DD} = 3\text{ V} \pm 10\text{ mV}$ .
4. To guarantee less than 1%  $V_{REFOUT}$  deviation
5. Measured at  $V_{DD} = 3\text{ V} \pm 10\text{ mV}$ . This value takes into account  $V_{DD}$  accuracy and ADC conversion accuracy.



Table 49. Comparator 2 characteristics

Symbol	Parameter	Conditions	Min	Typ	Max <sup>(1)</sup>	Unit
$V_{DDA}$	Analog supply voltage	-	1.65		3.6	V
$V_{IN}$	Comparator 2 input voltage range	-	0		$V_{DDA}$	V
$t_{START}$	Comparator startup time	Fast mode	-	15	20	$\mu s$
		Slow mode	-	20	25	
$t_{d\ slow}$	Propagation delay <sup>(2)</sup> in slow mode	$1.65\ V \leq V_{DDA} \leq 2.7\ V$	-	1.8	3.5	
		$2.7\ V \leq V_{DDA} \leq 3.6\ V$	-	2.5	6	
$t_{d\ fast}$	Propagation delay <sup>(2)</sup> in fast mode	$1.65\ V \leq V_{DDA} \leq 2.7\ V$	-	0.8	2	
		$2.7\ V \leq V_{DDA} \leq 3.6\ V$	-	1.2	4	
$V_{offset}$	Comparator offset error	-	-	$\pm 4$	$\pm 20$	mV
$d_{Threshold}/dt$	Threshold voltage temperature coefficient	$V_{DDA} = 3.3V$ $T_A = 0\ to\ 50\ ^\circ C$ $V_- = V_{REF+},\ 3/4$ $V_{REF+},$ $1/2\ V_{REF+},\ 1/4\ V_{REF+}$	-	15	30	ppm/ $^\circ C$
$I_{COMP2}$	Current consumption <sup>(3)</sup>	Fast mode	-	3.5	5	$\mu A$
		Slow mode	-	0.5	2	

1. Based on characterization.
2. The delay is characterized for 100 mV input step with 10 mV overdrive on the inverting input, the non-inverting input set to the reference.
3. Comparator consumption only. Internal reference voltage (necessary for comparator operation) is not included.

### 9.3.13 12-bit DAC characteristics

In the following table, data are guaranteed by design.

**Table 50. DAC characteristics**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$V_{DDA}$	Analog supply voltage	-	1.8	-	3.6	V
$V_{REF+}$	Reference supply voltage	-	1.8	-	$V_{DDA}$	
$I_{VREF}$	Current consumption on $V_{REF+}$ supply	$V_{REF+} = 3.3$ V, no load, middle code (0x800)	-	130	220	$\mu$ A
		$V_{REF+} = 3.3$ V, no load, worst code (0x000)	-	220	350	
$I_{VDDA}$	Current consumption on $V_{DDA}$ supply	$V_{DDA} = 3.3$ V, no load, middle code (0x800)	-	210	320	
		$V_{DDA} = 3.3$ V, no load, worst code (0x000)	-	320	520	
$T_A$	Temperature range		-40	-	125	$^{\circ}$ C
$R_L^{(1)(2)}$	Resistive load	DACOUT buffer ON	5	-	-	k $\Omega$
$R_O$	Output impedance	DACOUT buffer OFF	-	8	10	k $\Omega$
$C_L^{(3)}$	Capacitive load		-	-	50	pF
DAC_OUT <sub>(4)</sub>	DAC_OUT voltage	DACOUT buffer ON	0.2	-	$V_{DDA} - 0.2$	V
		DACOUT buffer OFF	0	-	$V_{REF+} - 1$ LSB	V
$t_{settle}$	Settling time (full scale: for a 12-bit input code transition between the lowest and the highest input codes when DAC_OUT reaches the final value $\pm 1$ LSB)	$R_L \geq 5$ k $\Omega$ , $C_L \leq 50$ pF	-	7	12	$\mu$ s
Update rate	Max frequency for a correct DAC_OUT (@95%) change when small variation of the input code (from code i to i+1LSB).	$R_L \geq 5$ k $\Omega$ , $C_L \leq 50$ pF	-	-	1	Msp/s
$t_{WAKEUP}$	Wakeup time from OFF state. Input code between lowest and highest possible codes.	$R_L \geq 5$ k $\Omega$ , $C_L \leq 50$ pF	-	9	15	$\mu$ s
PSRR+	Power supply rejection ratio (to $V_{DDA}$ ) (static DC measurement)	$R_L \geq 5$ k $\Omega$ , $C_L \leq 50$ pF	-	-60	-35	dB

1. Resistive load between DACOUT and GNDA
2. Output on PF0 or PF1
3. Capacitive load at DACOUT pin
4. It gives the output excursion of the DAC

### 9.3.14 12-bit ADC1 characteristics

In the following table, data are guaranteed by design.

**Table 53. ADC1 characteristics**

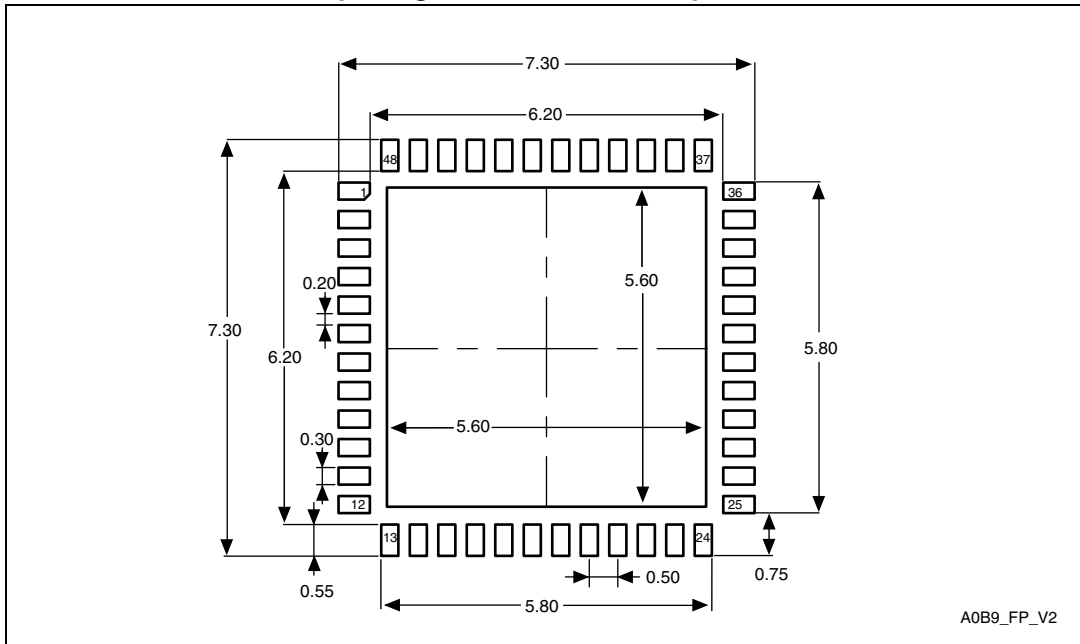
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$V_{DDA}$	Analog supply voltage	-	1.8		3.6	V
$V_{REF+}$	Reference supply voltage	$2.4\text{ V} \leq V_{DDA} \leq 3.6\text{ V}$	2.4		$V_{DDA}$	
		$1.8\text{ V} \leq V_{DDA} \leq 2.4\text{ V}$	$V_{DDA}$			
$V_{REF-}$	Lower reference voltage	-	$V_{SSA}$			
$I_{VDDA}$	Current on the $V_{DDA}$ input pin	-	-	1000	1450	$\mu\text{A}$
$I_{VREF+}$	Current on the $V_{REF+}$ input pin	-	-	400	700 (peak) <sup>(1)</sup>	
		-	-		450 (average) <sup>(1)</sup>	
$V_{AIN}$	Conversion voltage range	-	0 <sup>(2)</sup>	-	$V_{REF+}$	
$T_A$	Temperature range	-	-40	-	125	$^{\circ}\text{C}$
$R_{AIN}$	External resistance on $V_{AIN}$	on PF0/1/2/3 fast channels	-	-	50 <sup>(3)</sup>	$\text{k}\Omega$
		on all other channels	-	-		
$C_{ADC}$	Internal sample and hold capacitor	on PF0/1/2/3 fast channels	-	16	-	$\mu\text{F}$
		on all other channels	-		-	
$f_{ADC}$	ADC sampling clock frequency	$2.4\text{ V} \leq V_{DDA} \leq 3.6\text{ V}$ without zooming	0.320	-	16	MHz
		$1.8\text{ V} \leq V_{DDA} \leq 2.4\text{ V}$ with zooming	0.320	-	8	
$f_{CONV}$	12-bit conversion rate	$V_{AIN}$ on PF0/1/2/3 fast channels	-	-	1 <sup>(3)(4)</sup>	kHz
		$V_{AIN}$ on all other channels	-	-	760 <sup>(3)(4)</sup>	
$f_{TRIG}$	External trigger frequency	-	-	-	$t_{conv}$	$1/f_{ADC}$
$t_{LAT}$	External trigger latency	-	-	-	3.5	$1/f_{SYSCLK}$

**Table 66. UFQFPN48 - 48-lead, 7x7 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package mechanical data**

Symbol	millimeters			inches <sup>(1)</sup>		
	Min	Typ	Max	Min	Typ	Max
A	0.500	0.550	0.600	0.0197	0.0217	0.0236
A1	0.000	0.020	0.050	0.0000	0.0008	0.0020
D	6.900	7.000	7.100	0.2717	0.2756	0.2795
E	6.900	7.000	7.100	0.2717	0.2756	0.2795
D2	5.500	5.600	5.700	0.2165	0.2205	0.2244
E2	5.500	5.600	5.700	0.2165	0.2205	0.2244
L	0.300	0.400	0.500	0.0118	0.0157	0.0197
T	-	0.152	-	-	0.0060	-
b	0.200	0.250	0.300	0.0079	0.0098	0.0118
e	-	0.500	-	-	0.0197	-
ddd	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

**Figure 58. UFQFPN48 - 48-lead, 7x7 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package recommended footprint**



1. Dimensions are expressed in millimeters.

**Table 70. Document revision history (continued)**

Date	Revision	Changes
03-Apr-2013	5	<p>Updated capacitive sensing channels and “Dynamic consumption” in <a href="#">Features</a></p> <p>Updated LCD feature in <a href="#">Table 2: High-density and medium+ density STM8L15xx6/8 low power device features and peripheral counts</a></p> <p>Updated Halt mode definition in <a href="#">Section 3.1: Low-power modes</a></p> <p>Added <a href="#">Bootloader</a></p> <p>Updated <a href="#">Section 3.12: System configuration controller and routing interface</a></p> <p>Added <a href="#">Section 3.13: Touch sensing</a></p> <p><a href="#">Table 5: High-density and medium+ density STM8L15x pin description</a>: updated NRST/PA1, PI0, PI1, PI2, PE0, PE1, PE2, PF4, PF5, PF6, PF7, footnote <a href="#">1</a>. and added <a href="#">Note</a>:</p> <p>Updated ‘0x00 502E to 0x00 5049’ reserved area in <a href="#">Table 9: General hardware register map</a></p> <p>Updated reference to SWIM/DEBUG manual in <a href="#">Section 7: Option bytes</a></p> <p>Updated BOR factory default settings to 0x00 in <a href="#">Table 12: Option byte addresses</a></p> <p>Corrected ROP option byte value in <a href="#">Table 12: Option byte addresses</a></p> <p>Added <a href="#">Figure 45: Maximum dynamic current consumption on VREF+ supply pin during ADC conversion</a></p> <p>Updated STABVREFINT max value in <a href="#">Table 46: Reference voltage characteristics</a></p> <p>Updated <a href="#">Figure 41: SPI1 timing diagram - master mode</a></p> <p>Added <a href="#">Table 57: RAIN max for fADC = 16 MHz</a></p> <p>Updated Max DAC_OUT in <a href="#">Table 50: DAC characteristics</a></p> <p>Updated <a href="#">Section 9.3.12: Comparator characteristics</a></p>
31-Jul-2013	6	<p>Added ‘Top view’ footnotes under the pinout figures in <a href="#">Section 4: Pin description</a></p> <p>Updated the PF4-PF7 pins for the LQFP80 in <a href="#">Table 5: High-density and medium+ density STM8L15x pin description</a></p> <p>Updated all packages:</p> <p>Updated <a href="#">Figure 57: UFQFPN48 - 48-lead, 7x7 mm, 0.5 mm pitch, ultra thin fine pitch quad flat package outline</a> and <a href="#">Table 65: LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package mechanical data</a></p> <p>Added <a href="#">Figure 49: LQFP80 - 80-pin, 14 x 14 mm low-profile quad flat package recommended footprint</a></p> <p>Added ‘tape and reel’ in <a href="#">Table 69: Ordering information scheme</a></p>